


<b>Search Notes</b>  	<b>Application/Control No.</b>  10531753	<b>Applicant(s)/Patent Under Reexamination</b>  NESZ ET AL.
	<b>Examiner</b>  SHAQ TAHA	<b>Art Unit</b>  2446

SEARCHED			
Class	Subclass	Date	Examiner
709	227	10/16/2008	S. Taha
709	227	03/25/2009	S. Taha
709	227	12/20/2009	S. Taha
709	227	09/02/2010	S. Taha

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	09/10/2008	S. Taha
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	03/25/2009	S. Taha
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	12/20/2009	S. Taha
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 709/223,224,225,226,228,229	09/02/2010	S. Taha

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/S. T./ Examiner.Art Unit 2446	
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